PATENT ASSIGNMENT

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SUBMISSION TYPE:	NEW ASSIGNMENT
NATURE OF CONVEYANCE:	ASSIGNMENT

CONVEYING PARTY DATA

Name	Execution Date
Alexander P. Cherkassky	06/18/2008

RECEIVING PARTY DATA

Name:	Nanometrics Incorporated
Street Address:	1550 Buckeye Drive
City:	Milpitas
State/Country:	CALIFORNIA
Postal Code:	95035

PROPERTY NUMBERS Total: 1

Property Type	Number
Patent Number:	6242739

OP $40.00 6242739

CORRESPONDENCE DATA

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NAME OF SUBMITTER:	Michael J. Halbert

Total Attachments: 2
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ASSIGNMENT

For good and valuable consideration, receipt of which is hereby acknowledged, I:

Alexander P. Cherkassky of 26408 Shore Harbor Drive, #N, Germantown, MD 20874;

hereby sell, assign and transfer to **Nanometrics Incorporated**, a Delaware corporation, having a place of business at 1550 Buckeye Drive, Milpitas, CA 95035-7418, its successors and assigns, the entire right, title and interest in an invention for which United States patent applications were filed and a patent issued as listed below, as well as all patent applications and patents of every country for said invention including those listed below, and including divisions, reissues, continuations, and extensions thereof, and to claim all rights of priority without further authorization.

Country (Region)	Patent Number:	Issued:	Application Number:	Filing Date:	Title:
Australia			App No: 35718/99 Ser. No: 7431388	10/13/2000	Non-Destructive Analysis Of A Semiconductor Using Reflective Spectometry
Canada			2328624	10/12/2000	Non-Destructive Analysis Of A Semiconductor Using Reflective Spectometry
EPC	EP1078217	6/9/2004	99917648	11/21/2000	Non-Destructive Analysis Of A Semiconductor Using Reflective Spectometry
France	EP1078217	6/9/2004	99917648	4/20/1999	Analyse Non-Destructive De Semi-Conducteur Par Spectrometrie Par Reflectance
Germany	EP1078217	6/9/2004	99917648	4/20/1999	Zerstoerungsfreie Analyse Eines Halbleiters Mittels Reflektionsspektrometrie
Great Britain	EP1078217	6/9/2004	99917648	4/20/1999	Non-Destructive Analysis Of A Semiconductor Using Reflective Spectometry
Italy	EP1078217	6/9/2004	99917648	4/20/1999	Non-Destructive Analysis Of A Semiconductor Using Reflective Spectometry
Japan			2000-544982	10/23/2000	Non-Destructive Analysis Of A Semiconductor Using Reflective Spectometry
United States	6,242,739	6/5/2001	09/294,247	4/19/1999	Method And Apparatus For Non-Destructive Determination Of Film Thickness And Dopant Concentration Using Fourier Transform Infrared Spectometry
United States			60/082,639	4/21/1998	Method And Apparatus For Non-Destructive Determination Of Film Thickness And Dopant Concentration Using Fourier Transform Infrared Spectometry
PCT	Pub No: WO/99/054679	Pub Date: 10/28/1999	PCT/US99/008721	4/20/1999	Non-Destructive Analysis Of A Semiconductor Using Reflectance Spectrometry

Further, I agree to execute all papers useful in connection with the above-identified patents and patent applications as well as any other patent and patent applications related to said invention, and generally to do everything possible to aid said assignee, its successors, assigns and nominees, at their request and expense, in obtaining and enforcing patents for said invention in all countries; and I request that the United

States Patent and Trademark Office and foreign patent offices issue all patents granted for said invention to the above-named assignee, its successors and assigns.

Executed this 18 day of June, 2008.

Signature of Alexander P. Cherkassky

State of Texas)
County of Collin) ss.
On 6/18/2008 before me, Elena E. Heuer
(date) (Notary's Name)

Personally appeared Alexander P. Cherkassky who proved to me on the basis of satisfactory evidence to be the person whose name is subscribed to the within instrument and acknowledged to me that he/she executed the same in his/her authorized capacity, and that by his/her signature on the instrument the person, or the entity upon behalf of which the person acted, executed the instrument.

I certify under PENALTY OF PERJURY under the laws of the State of California that the foregoing paragraph is true and correct.
WITNESS my hand and official seal.

Elena E. Heuer
SIGNATURE OF NOTARY

ELENA E. HEUER
Notary Public, State of Texas
My Comm. Expires Sept. 22, 2011